

Investigation of an analytical Aberration Description for Alvarez-Lohmann type Phase Plates

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Motivation - Alvarez Lohmann Lenses

Alvarez-Lohmann Lenses^[1,2]

- two cubic functions in combination generate a parabolic function
- curvature of the parabolic function linearly dependent on lateral shift of the functions

$$W(x, y) = A(x^2 y + \frac{y^3}{3})$$

$$W(x, y - h) - W(x, y + h)$$

$$= A(x^2(y - h) + \frac{(y - h)^3}{3}) - A(x^2(y + h) + \frac{(y + h)^3}{3})$$

$$= -2hA(x^2 + y^2) - \frac{2Ah^3}{3}$$

Problem:

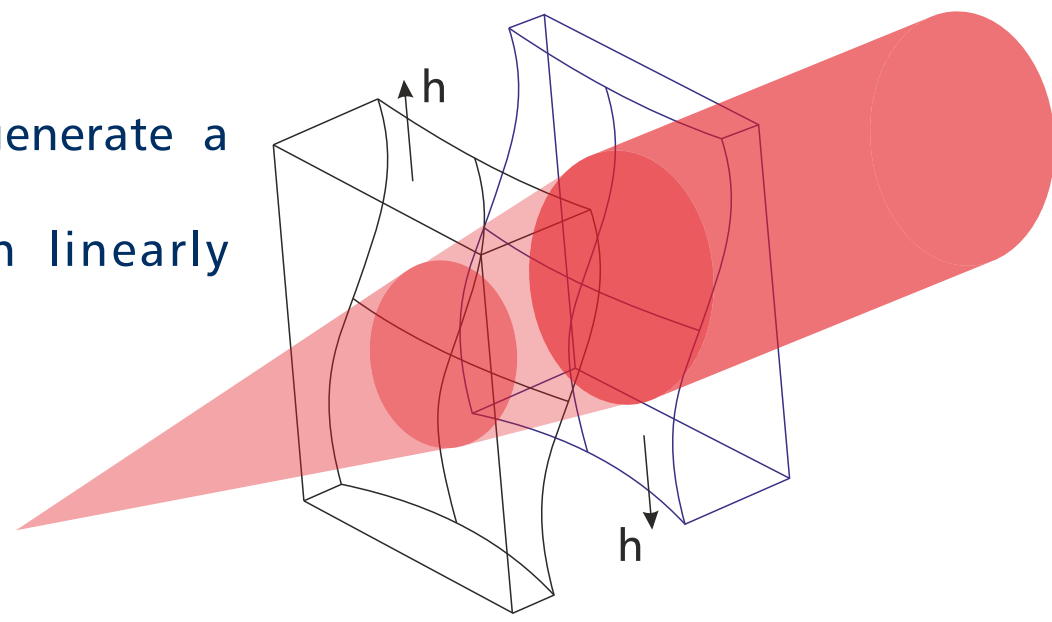
- model based on thin element approximation
- distance between elements and element thickness induce aberrations to the system^[3]

Goal:

- analytical approximation of induced aberrations
- comparison of the analytical model with other models:
 - > commercial ray tracing software
 - > Fresnel wave propagation (propagator: $\exp(ij \ 2\pi \Delta z \sqrt{\frac{1}{\lambda^2} - f_x^2 - f_y^2})$)

Approximations:

- thin phase elements (DOEs) with distances in between
- near paraxial region



Aberrations: Ray Tracing, Wave Propagation and Analytical Model

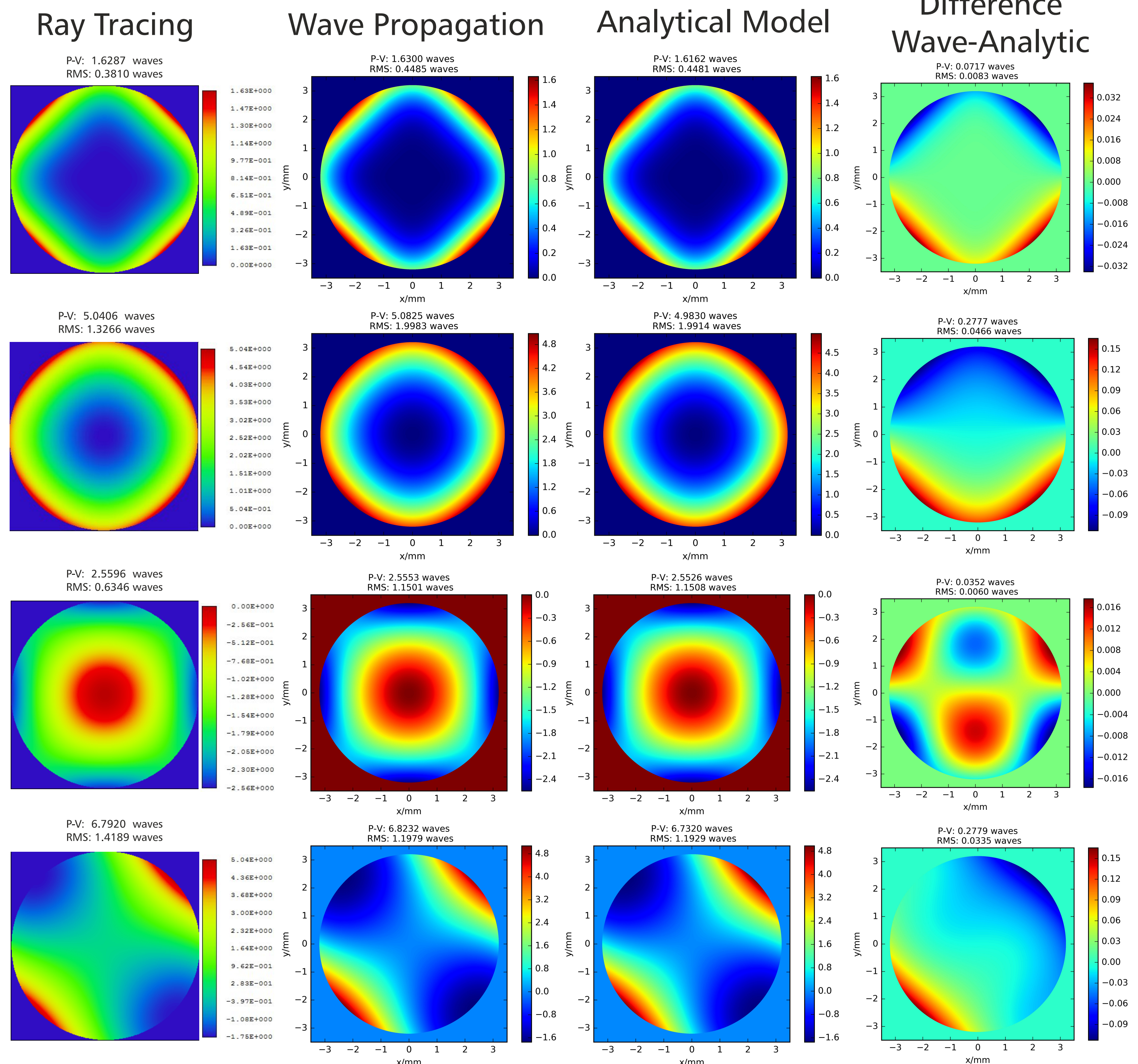
Field angles:
 α - around y
 β - around x

$\alpha = 0$
 $\beta = 0$

$\alpha = 0$
 $\beta = 5$

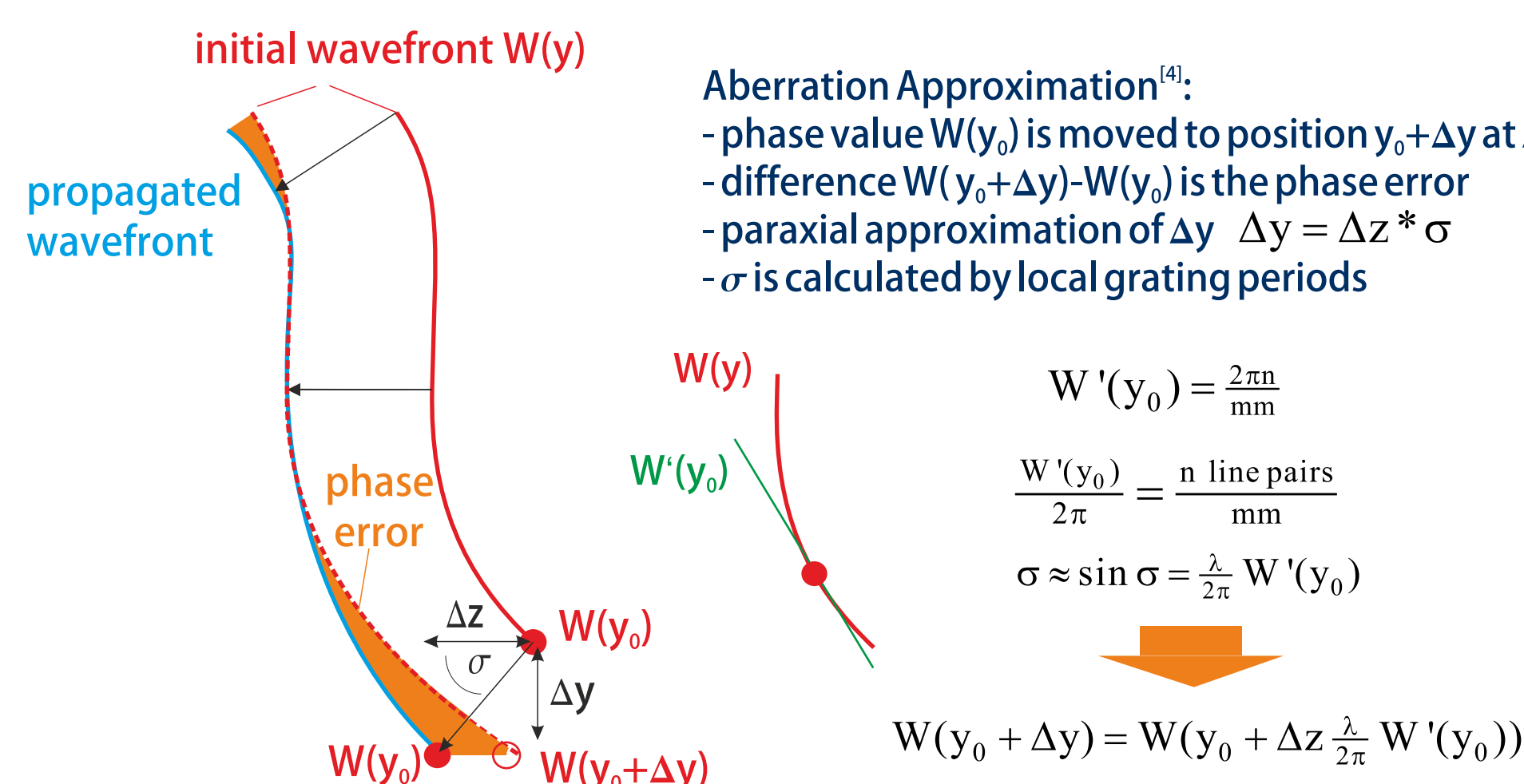
$\alpha = 0$
 $\beta = -5$

$\alpha = 5$
 $\beta = 0$



System Data: axial distance $\Delta z = 0.5$ mm; object at infinity; $A = 30 \cdot 10^9 / \text{m}^3 \rightarrow$ min. grating period $9 \mu\text{m}$; $h = 0$

Simplified Propagation Model



- different angles of incidence can be considered in the lateral offset Δy
- an expansion to 3D functions is achieved by partial derivatives

$$W(x_0 + \Delta x, y_0 + \Delta y) = W(x_0 + \Delta z \frac{\lambda}{2\pi} W'_x(x_0, y_0) + \alpha, y_0 + \Delta z \frac{\lambda}{2\pi} W'_y(x_0, y_0) + \beta)$$

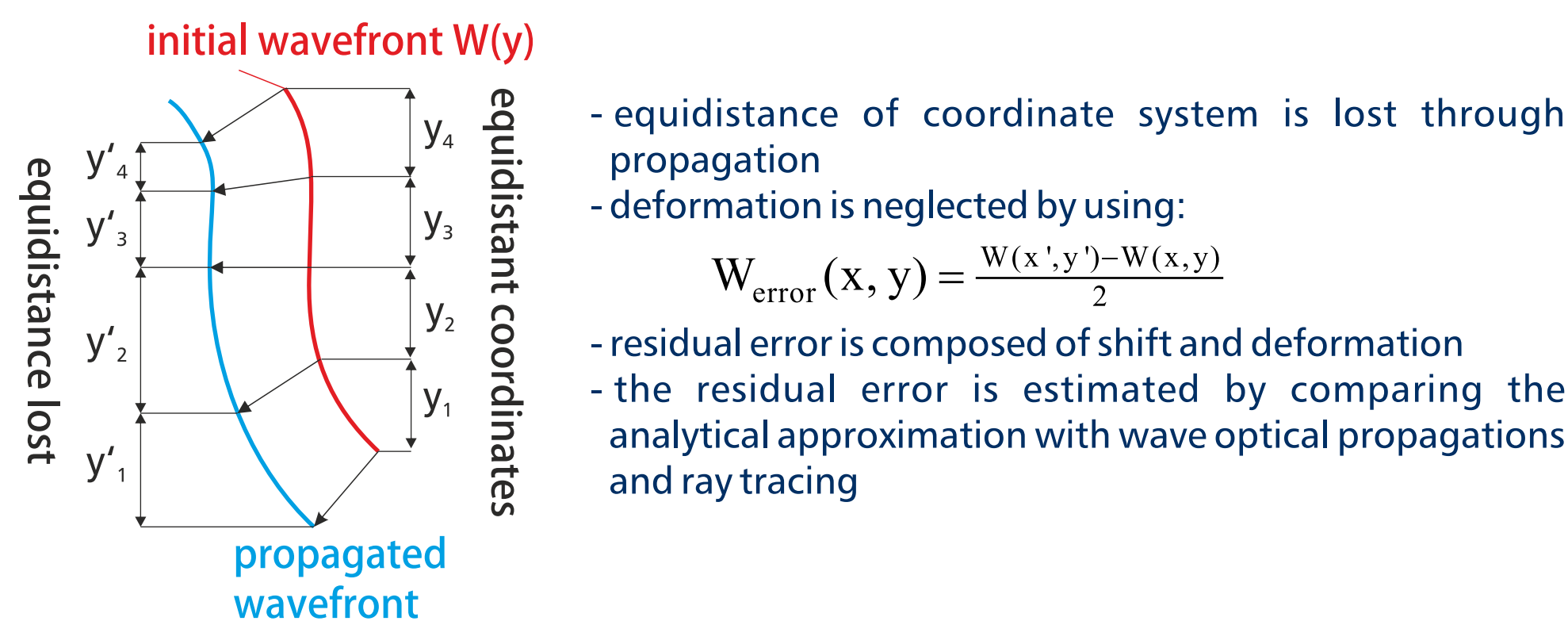
Application to Alvarez-Lohmann lenses for $\alpha = \beta = 0$

$$W(x_0 + \Delta x, y_0 + \Delta y) = A((x_0 + \Delta x)^2(y_0 + \Delta y) + \frac{(y_0 + \Delta y)^3}{3})$$

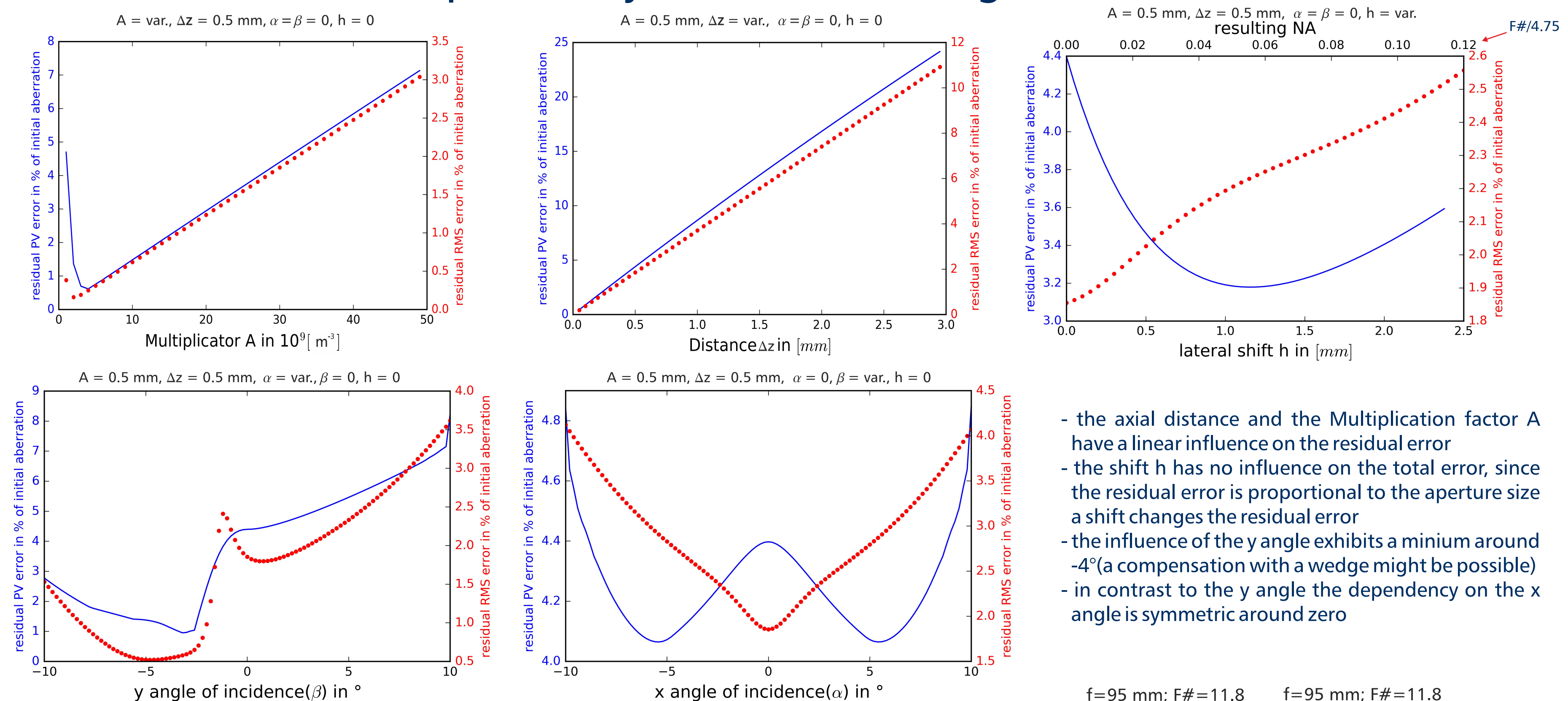
$$= A((x_0 + \Delta z \frac{\lambda}{2\pi} (2Ax_0 y_0))^2(y_0 + \Delta z \frac{\lambda}{2\pi} A(x_0^2 + y_0^2)) + \frac{(y_0 + \Delta z \frac{\lambda}{2\pi} A(x_0^2 + y_0^2))^3}{3})$$

$$= A((x_0^2 y_0 + \frac{y_0^3}{3}) + \Delta z \frac{\lambda}{2\pi} A^2(x_0^4 + 6x_0^2 y_0^2 + y_0^4) + (\Delta z \frac{\lambda}{2\pi})^2 A^3(5x_0^4 y_0 + 10x_0^2 y_0^3 + y_0^5) + (\Delta z \frac{\lambda}{2\pi})^3 A^4(\frac{8x_0^6}{3} + 5x_0^4 y_0^2 + 5x_0^2 y_0^4 + \frac{y_0^6}{3}))$$

Coordinate system deformations - a source of residual errors



Residual Error - Dependency on distance, angle, shift and coefficient A



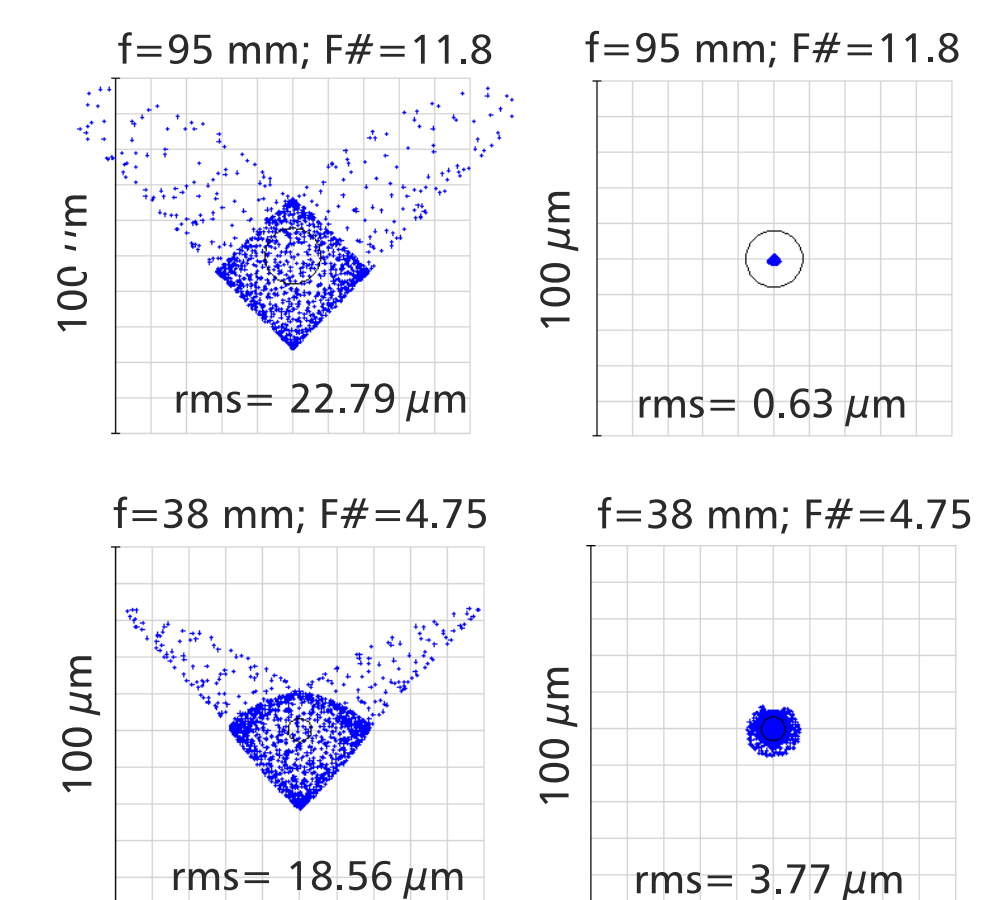
- the axial distance and the Multiplication factor A have a linear influence on the residual error
- the shift h has no influence on the total error, since the residual error is proportional to the aperture size a shift changes the residual error
- the influence of the y angle exhibits a minimum around -4° (a compensation with a wedge might be possible)
- in contrast to the y angle the dependency on the x angle is symmetric around zero

Error Compensation

- the analytical error function can be subtracted from the description of the first phase element
- since each angle of incidence generates a different error function an analytical compensation over a range of view is not possible
- the compensation function is a compromise for all field positions

on axis spot diagrams for a system of Alvarez Lohmann DOEs

- element thickness 1 mm, $\Delta z = 0.5$ mm and $\sigma = 8$ mm
- left: original element function
- right: error subtracted from first element function



Conclusion & Outlook

- an analytical approximation for aberrations in Alvarez-Lohmann type phase plates was derived from [4] and compared to ray tracing and wave propagation methods
- due to the paraxial character of the model its accuracy decreases for large angles

- next steps are to investigate an analytical weighting of the error function for different field points and check the accuracy of the model for refractive elements
- analyzing the weighting factor „2“ in the error description

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